

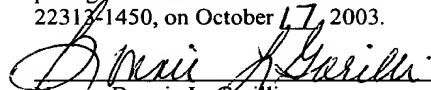
2814
Docket No. 740756-2183

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Patent Application of)
Shunpei YAMAZAKI)
Serial No. 09/620,968) Examiner: Nathan W. Ha
Filed: July 20, 2000) Group Art Unit: 2814
For: METHOD OF FORMING INSULATION FILMS,) Confirmation No. 4214
CAPACITANCES, AND SEMICONDUCTOR DEVICES)

Certificate of Mailing

I hereby certify that this correspondence is being deposited with the United States Postal Service with sufficient postage for First Class Mail in an envelope addressed to: Commissioner for Patents, P. O. Box 1450, Alexandria, VA 22313-1450, on October 17, 2003.


Name: Bonnie L. Garlin

REQUEST FOR ACKNOWLEDGMENT OF
INFORMATION DISCLOSURE STATEMENT

Commissioner for Patents
Alexandria, VA 22313-1450

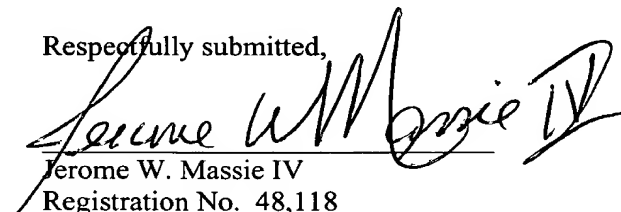
Sir:

An Information Disclosure Statement with Form PTO-1449 was filed in the above-identified patent application on July 20, 2000. Applicants have not yet received back from the Examiner a copy of the Form PTO-1449 initialed to acknowledge the fact that the Examiner has considered the cited disclosed information.

The Examiner is requested to initial and return to the undersigned a copy of the subject Form PTO-1449.

Should there be any questions concerning this communication, please telephone the undersigned at the number set forth below.

Respectfully submitted,


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Form PTO-1449
(Rev. 8-83)U.S. Department of Commerce
Patent and Trademark Office

Attorney Docket No. 0756-2183

Serial No. Not Yet Assigned

INFORMATION DISCLOSURE STATEMENT

(Use several sheets if necessary)

Applicant: Shunpei YAMAZAKI

Filing Date: July 20, 2000

Group: 2811

U.S. PATENT DOCUMENTS

Examiner Initial	Document Number	Date	Name	Class	Subclass	Filing Date (if appropriate)
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*EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

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	definition from Merriam Webster Collegiate Dictionary, Tenth Edition
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	5,136,534	08/04/92	McDavid et al.			

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WO 89/02655	03/23/89	PCT			Full
JP 01-171275	7/6/89	Japan			Abstract
JP 62-23117	1/31/87	Japan			Abstract
JP 62-298119	12/25/87	Japan			Abstract
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JP 03-16129	24/1/91	Japan			Abstract
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63-199456	8/17/88	Japan			X
1-248557	10/4/89	Japan			X
2-79475	3/20/90	Japan			X

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						Yes	No
	JP 59-99726	6/8/84	Japan			Abstract	
	JP 64-82557	03/28/89	Japan			Abstract	
	JP 01-225148	09/08/89	Japan			Abstract	
	JP 04-61337	02/27/92	Japan			Abstract	
	60-005555	01/12/85	Japan			Abstract	
	60-218472	11/01/85	Japan			Abstract	
	61-119045	06/06/86	Japan			Abstract	
	62-056570	03/12/87	Japan			Abstract	
	63-096262	04/27/88	Japan			Abstract	
	1-218054	08/31/89	Japan			Abstract	

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